

Applicat	ation/Control No. Applicant(s)/Patent under Reexamination		nt under
10/710,3	395	CHEN ET AL.	
Examine	r	Art Unit	
Yewebd	ar T. Tadesse	1734	

	OF A POUED					
SEARCHED						
Class	Subclass	Date	Examiner			
118	52,612	8/3/2005	YTT			
118	666,668	8/3/2005	YTT			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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DATE	EXMR
8/3/2005	YTT
8/3/2005	YTT
1/20/2006	YTT
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